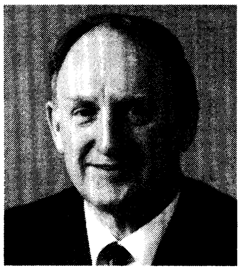

Communications—A New Section in *Optical Engineering*

I am pleased to announce a new section of our journal that appears in this month's issue. The section is called "Communications" and will be included as needed as a separate section following the technical papers.

The purpose of this new section is to publish short communications on original work, comments on recent papers, and errata. It will be my responsibility to determine what material is accepted for publication and, when necessary, I will seek outside reviewers' assistance. This is not meant to be a "letter to the editor" section where writers comment on issues of the day, whether political or scientific. Contributions must be technical in nature and add something positive to our further understanding of our field of optical science and engineering.

I encourage your submissions to our new "Communications."

Electronic Imaging—A New Journal

I am pleased to bring a new journal to your attention. This new publication, called the *Journal of Electronic Imaging*, is copublished by SPIE—The International Society for Optical Engineering and IS&T—The Society for Imaging Science and Technology. The first issue of this new journal was published in time for the Symposium on Electronic Imaging Science and Technology held in San Jose, California, February 9–14, 1992. Like the *Journal of Electronic Imaging*, the conference was cosponsored by SPIE and IS&T.

We welcome Editor Paul Roetling and Associate Editor Majid Rabbani to the brotherhood of editors. I will be working closely with Paul to ensure that the right papers appear in the right journals.

The *Journal of Electronic Imaging* will appear quarterly and cover all technology areas that make up the field of electronic imaging and are normally considered in the design, engineering, and application of an electronic imaging system. The following research areas, whether they apply directly to electronic imaging or focus on applied electronic imaging technology, will be covered:

- Image acquisition
- Image data storage
- Image data communication
- Display of image data
- Hard copy output
- Image visualization
- Image processing
- Electronic imaging application.

The *Journal of Electronic Imaging* has been created in response to the need for a refereed journal dedicated to technical problems, issues, and progress in the field of electronic imaging. Its objective is to address the full spectrum of electronic imaging technologies from the standpoint of technical innovation, systems integration, and application, and therefore meet the needs of readers and authors working in this field.

The two societies, SPIE and IS&T, and the editors of the new journal invite your active participation as both reader and author. Manuscripts should be submitted to:

Paul G. Roetling
Journal of Electronic Imaging
Xerox Webster Research Center
Building 128-27E
800 Phillips Road
Webster, New York 14580.

Brian J. Thompson
Editor

Optical Engineering Editorial Schedule

May 1992
Optical Implementation of Information Processing, Pattern Recognition, and Neural Networks
Bahram Javidi
University of Connecticut
Department of Electrical and Systems Engineering
Room 312, U-157
260 Glenbrook Road
Storrs, CT 06269-3157
203/486-2867 • 203/486-0318 FAX

June 1992
Adaptive Signal Processing
Simon Haykin
McMaster University
Communications Research Laboratory
1280 Main Street West
Hamilton, Ontario L8S 4K1 Canada
416/525-9140

August 1992
Optical Engineering and U.K. Industry
Lionel R. Baker
Sira Ltd.
South Hill, Chislehurst
Kent BR7 5EH, United Kingdom
+44 81 467 2636 • +44 81 467 6515 FAX
R. J. Parker
Rolls Royce plc
P.O. Box 31
Derby DE2 8BJ, United Kingdom

September 1992
Wavelet Transform
Harold H. Szu
U.S. Navy
Naval Surface Warfare Center, Code R44
10901 New Hampshire Ave.
Silver Spring, MD 20903-5000
301/394-3097 • 301/394-3923 FAX

October 1992
Acousto-Optics
Ting-Chung Poon
Virginia Polytechnic Institute and State University
Bradley Department of Electrical Engineering
Optical Image Processing Laboratory
Blacksburg, VA 24061
703/231-4876 • 703/231-3362 FAX

November 1992
Relay Mirror Experiment
Paul W. Kervin
Phillips Laboratory
535 Lipoa Parkway, Suite 200
Kihei, HI 96753
808/874-1542 • 808/874-1640 FAX

December 1992
Automatic Target Recognition
Firooz Sadjadi
Systems and Research Center
Honeywell Inc.
3660 Technology Drive
Minneapolis, MN 55418
612/782-7543 • 612/782-7438 FAX

January 1993
Optical Research in Asia
Chung J. Kuo
National Chung Cheng University
Department of Electrical Engineering
Chiayi, Taiwan 62107
886-5-272-0411, ext. 6210 • 886-5-272-0862 FAX
Toshimitsu Asakura
Hokkaido University
Research Institute of Applied Electricity
Sapporo, 060 Japan
81-11-716-2111 • 81-11-758-3173 FAX
Yong H. Lee
KAIST Department of Physics
Yusung-Ku, Taejon, Korea
82-42-829-2536 • 82-42-861-1458 FAX
Run W. Wang
Shanghai Institute of Optics and Fine Mechanics
P.O. Box 800-211
Shanghai, 201800 China

February 1993
Biomedical Optics
Abraham Katzir
Tel Aviv University
School of Physics
69978 Tel Aviv, Israel
011-972-3-421648 • 011-972-3-415850 FAX
Manuscripts due June 15, 1992.

March 1993
Optical Fiber Reliability II
Hakan H. Yuce
Bellcore
445 South Street
Morristown, NJ 07962
201/829-4945 • 201/267-9753 FAX
Charles R. Kurkjian
AT&T Bell Laboratories
600 Mountain Avenue
Murray Hill, NJ 07960-1910
908/582-2378 • 908/582-2783 FAX
Manuscripts due July 15, 1992.

April 1993
Emerging Optoelectronic Technologies
Vijai K. Tripathi
Oregon State Univeristy
Dept. of Electrical and Computer Eng.
ECE Building 220
Corvallis, Oregon 97331-3211
503/737-3617 • 503/737-1300 FAX
Manuscripts due Sep. 1, 1992

May 1993
Phase Contrast Microscopy
Maksymilian Pluta
Institute of Applied Optics
ul. Kamionkowska 18
03-805 Warszawa, Poland
48 22 18 44 05 or 48 22 18 44 97
48 22 13 32 65 FAX

This special issue is connected with an international conference on Phase Contrast (PhC) and Differential Interference Contrast Microscopy, scheduled Oct. 19–21, 1992, in Warsaw, Poland, and organized by the Polish Chapter of SPIE. Topics will include theory and practice of phase micro-objects visualization, instrumentation for PhC microscopy, quantitative PhC techniques, linear phase microscopy, laser scanning differential PhC microscopy, scanning tunneling microscopy of phase objects, and new applications in biology/biomedicine and materials sciences. Manuscripts due Oct. 1, 1992.

June 1993
From Numerical to Symbolic Image Processing: Systems & Applications
G. Vernazza
Dipartimento di Ingegneria Biofisica ed Elettronica
Universita degli Studi di Genova
Via Opera Pia, 11a
16145 Genova, Italy
+39 10 353-2755 • +39 10 353-2777 FAX

This special issue will present innovative research and results on the integration between numerical and symbolic processing. Examples covering real applications will be considered. Manuscripts due Oct. 15, 1992.

July 1993
Visual Communication and Image Processing IV
Cheng-Tie Chen
Bellcore
445 South St.
Morristown, NJ 07962
201/829-5151 • 201/829-5884 FAX
Hsueh-Ming Hang
Center for Telecommunication Research
National Chiao-Tung University
Hsinchu, Taiwan
+886/35-712121 x3298 • +886/35-723283 FAX
Kou-Hu Tzou
COMSAT Labs.
22300 Comsat Drive
Clarksburg, MD 20871
301/428-4663 • 301/428-7747 FAX
Manuscripts due Dec. 1, 1992.

September 1993
Optical Science and Engineering in Canada
C.P. Grover
National Research Council
Institute for National Measurement Standards
Ottawa, Canada K1A OR6
613/993-2098 • 613/952-1394 FAX
Manuscripts due Feb. 1, 1993.

October 1993
Microlithography
James R. Sheats
Hewlett-Packard Company
2500 Deer Creek Road
Palo Alto, CA 94304-1392
415/857-5987 • 415/857-6241 FAX

This issue will cover the range of topics found in the SPIE Symposium on Microlithography (San Jose, Calif.), including resist materials, optical systems, and metrology. Manuscripts due March 1, 1993.

November 1993
Acquisition, Tracking, and Pointing
Mohammed A. Karim
University of Dayton
Center for Electro-Optics
300 College Park
Dayton, Ohio 45469-0227
513/229-2241 • 513/229-3433
Manuscripts due April 1, 1993.